

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/772,959 <b>Examiner</b> Tianjie Chen	<b>KIM ET AL.</b> <b>Art Unit</b> 2656	

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
360	97.02	12/5/2005	TJ